

Features <ul style="list-style-type: none"> ➤ Split Gate Trench MOSFET technology ➤ Excellent package for heat dissipation ➤ High density cell design for low $R_{DS(ON)}$ 	<i>Bvdss</i>	<i>Rdson</i>	<i>ID</i>
	-60V	3.6mΩ	-150A
Application <ul style="list-style-type: none"> ➤ DC-DC Converters ➤ Synchronous-rectification applications ➤ Power management functions 			
Package <div style="display: flex; justify-content: space-around; align-items: flex-end;"> <div style="text-align: center;"> <p>Marking and pin assignment</p> </div> <div style="text-align: center;"> <p>TO-220 top view</p> </div> <div style="text-align: center;"> <p>Schematic diagram</p> </div> </div>			

Package Marking and Ordering Information

Device Marking	Device	Device Package	Quantity
150P06	S150P06T	TO-220	50

Absolute Maximum Ratings ($T_J=25^{\circ}\text{C}$ unless otherwise specified)

Parameter	Symbol	Value	Unit	
Drain-Source Voltage	V_{DS}	-60	V	
Gate-Source Voltage	V_{GS}	± 20	V	
Continuous Drain Current	$T_C=25^{\circ}\text{C}$	I_D	-150	A
	$T_C=100^{\circ}\text{C}$	I_D	-91.7	A
Pulsed Drain Current	I_{DM}^1	-580	A	
Single Pulse Avalanche Energy	E_{AS}^2	2058	mJ	
Power Dissipation	$T_C = 25^{\circ}\text{C}$	P_D	183	W
Operating junction and storage temperature	T_J, T_{STG}	150, -55 ~ 150	$^{\circ}\text{C}$	
Maximum Temperature for Soldering	T_L	260	$^{\circ}\text{C}$	



Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Thermal Resistance Junction-Case	$R_{\theta JC}$	0.68	$^{\circ}C/W$
Thermal Resistance, Junction -to-Ambient	$R_{\theta JA}$	60	$^{\circ}C/W$

Ordering Information

Ordering Number	Package	Pin Assignment			Packing
Halogen Free		G	D	S	
HLS150P06T	TO-220	1	2	3	Tube

Electrical Characteristics ($T_j=25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=-250\mu A$	-60	-	-	V
Gate-body Leakage current	I_{GSS}	$V_{GS}=\pm 20V$	-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=-60V, V_{GS}=0V$	-	-	1	μA
Gate-Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=-250\mu A$	-2	-2.4	-2.8	V
Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS}=-10V, I_D=-20A$	-	3.6	4.3	m Ω
Input Capacitance	C_{ISS}	$V_{DS}=-30V, V_{GS}=0V,$ $f=1MHz$	-	9123	-	pF
Output Capacitance	C_{OSS}		-	1583	-	
Reverse Transfer Capacitance	C_{RSS}		-	85.6	-	
Gate Resistance	R_g	-	-	-	-	Ω
Total Gate Charge	Q_g	$V_{GS}=-10V, V_{DS}=-30V, I_D=-10A$	-	135	-	nC
Gate-Source Charge	Q_{gs}		-	28	-	
Gate-Drain Charge	Q_{gd}		-	22.4	-	
Turn-On Delay Time	$T_{d(on)}$	$V_{GS}=-10V, V_{DS}=-30V,$ $R_G=3\Omega, I_D=-10A$	-	70	-	ns
Rise Time	T_R		-	45	-	
Turn-Off Delay Time	$T_{d(off)}$		-	165	-	
Fall Time	T_F		-	50	-	
Diode Forward Current	I_S	$T_C=25^{\circ}C$	-	-	-150	A
Diode Forward Voltage	V_{SD}	$I_S=-20A, V_{GS}=0V$	-	-	-1.2	V
Reverse Recovery time	T_{rr}	$I_S=-10A, V_{DD}=-30V$ $di/dt=100A/\mu s$	-	45	-	ns
Reverse Recovery Charge	Q_{rr}		-	100	-	nC



Typical Performance Characteristics

Fig1:Typ. output characteristics

$I_D=f(-V_{DS})$

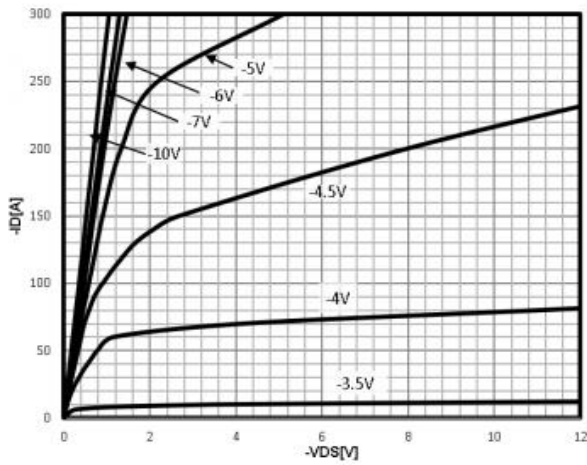


Fig2:Typ. drain-source on resistance

$R_{DS(on)}=f(-I_D)$

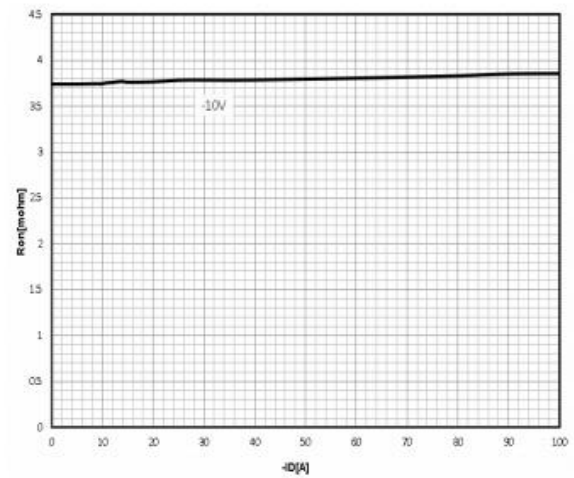


Fig3:Typ. transfer characteristics

$-I_D=f(-V_{GS})$

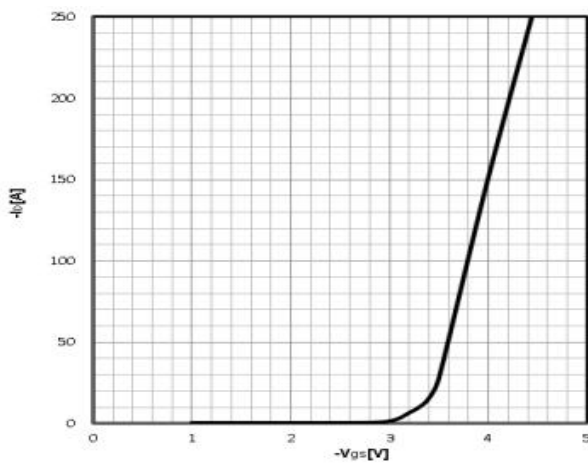


Fig4:Drain-source on-state resistance

$R_{DS(on)}=f(T_j); I_D=-20A; V_{GS}=-10V$

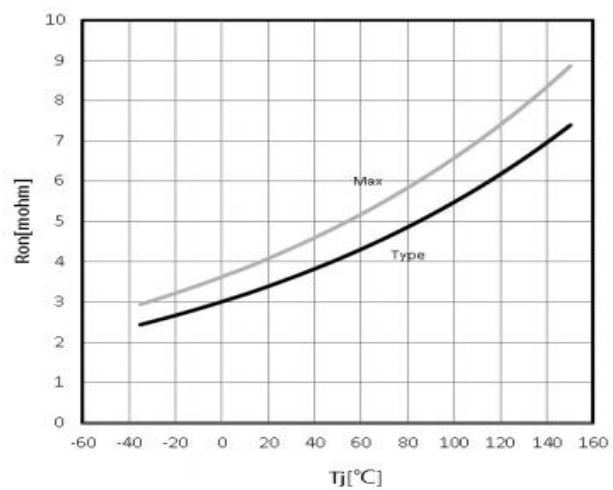


Fig5:Gate Threshold Voltage

$-V_{TH}=f(T_j); I_D=-250\mu A$

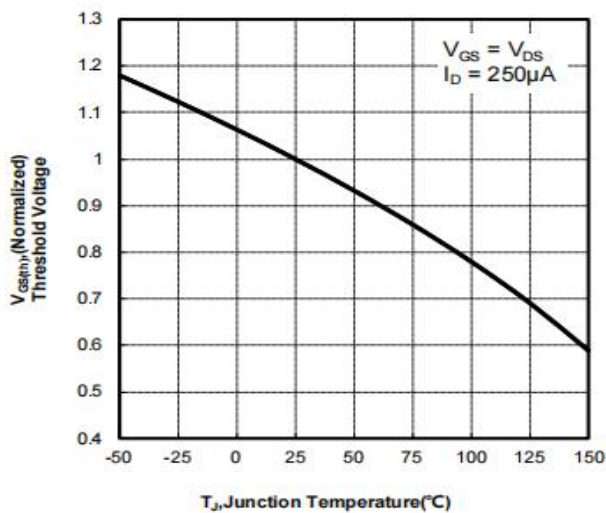


Fig6:Drain-source breakdown voltage

$V_{BR(DSS)}=f(T_j); I_D=-250\mu A$

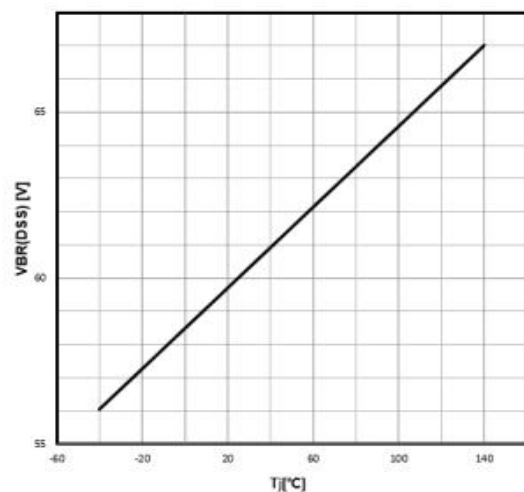




Fig7:Typ. gate charge

$V_{GS}=f(Q_g)$, $I_D=-10A$;

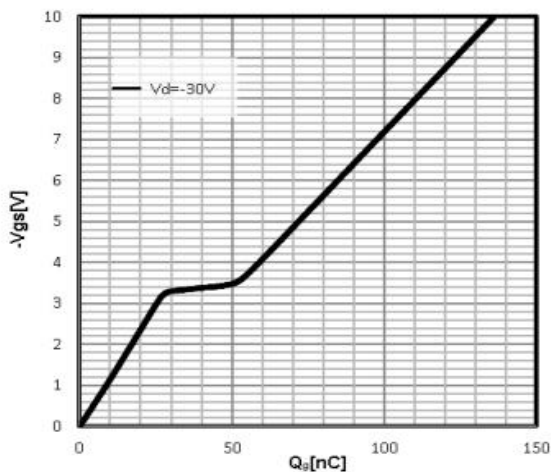


Fig8:Typ. capacitances

$C=f(V_{DS})$; $V_{GS}=0V$; $f=1MHz$

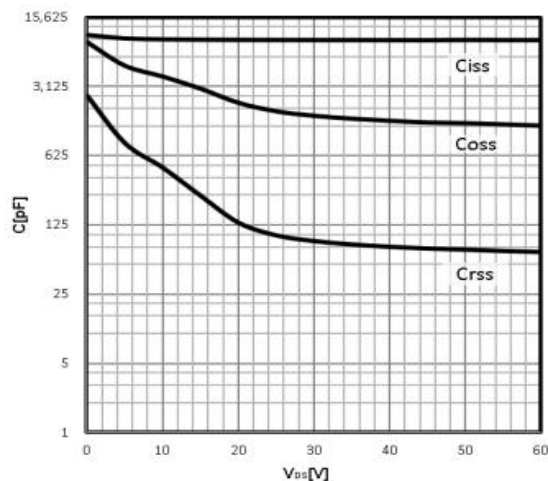


Fig9:Power Dissipation

$P_{tot}=f(T_c)$

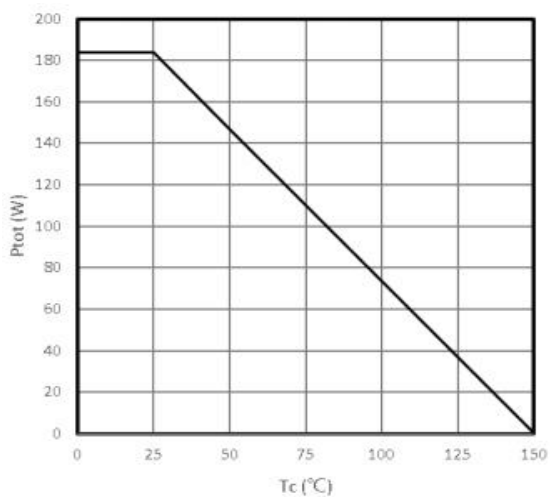


Fig10:Maximum Drain Current

$-I_D=f(T_c)$

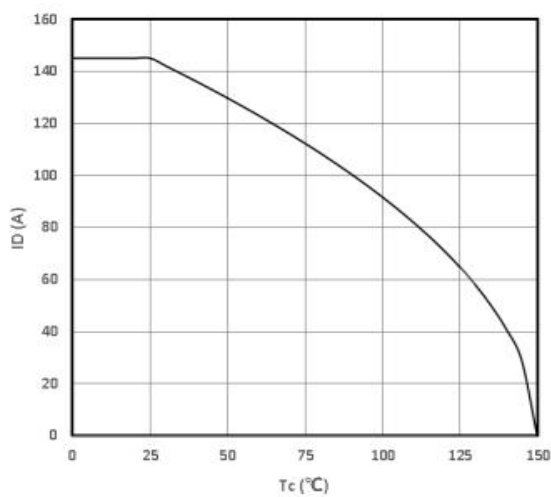


Fig11:Safe operating area

$I_D=f(V_{DS})$

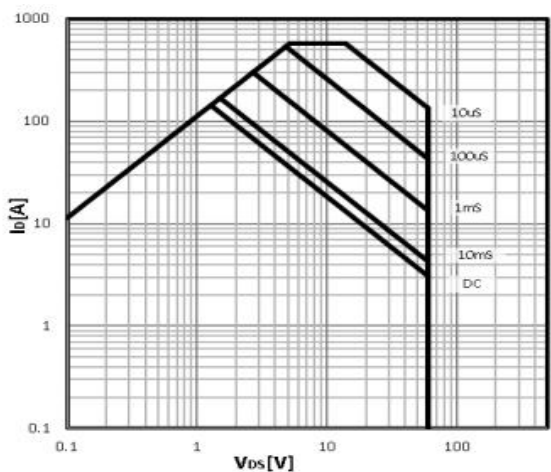


Fig12:Body Diode Forward Voltage Variation

$-I_F=f(-V_{DS})$

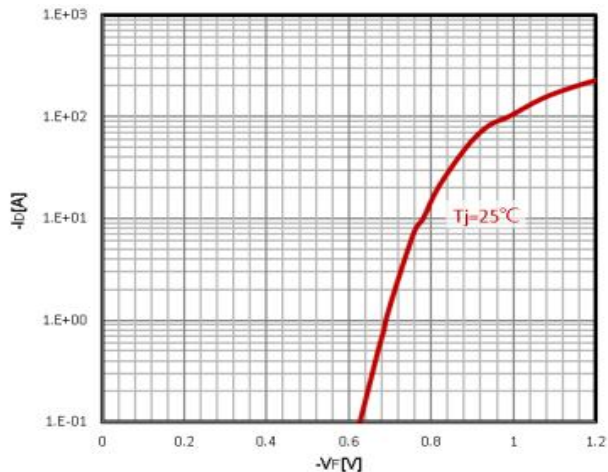
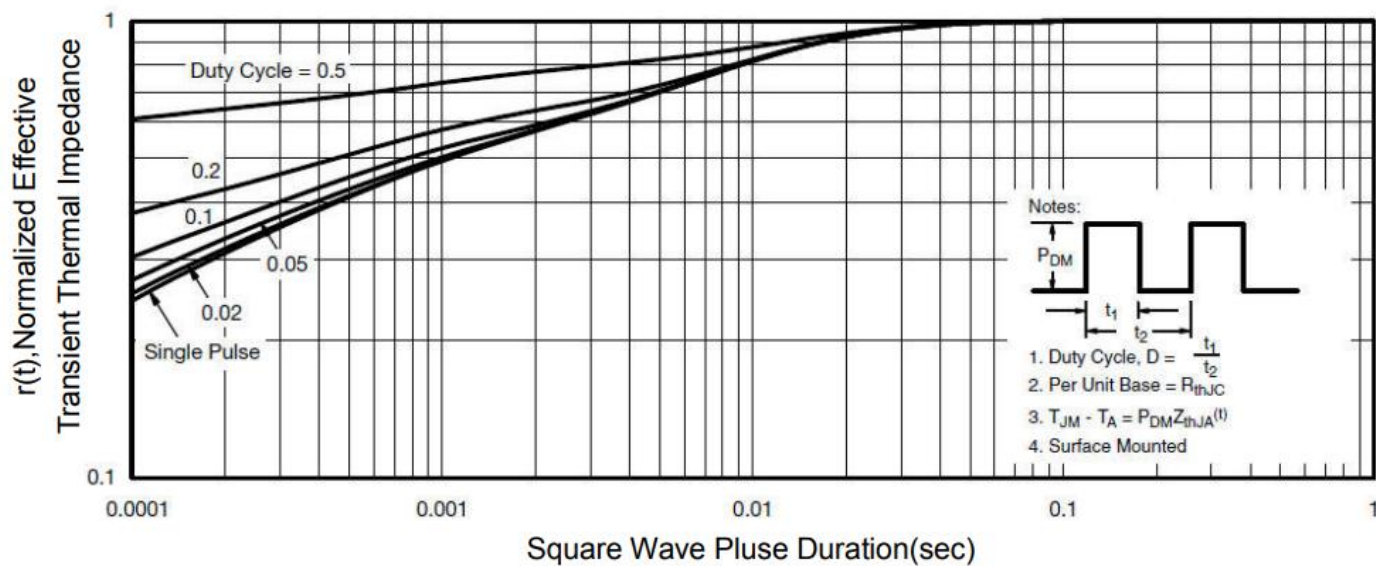


Figure 13: Max. Transient Thermal Impedance

$$Z_{thJC} = f(t_p)$$



Test Circuit and Waveform:

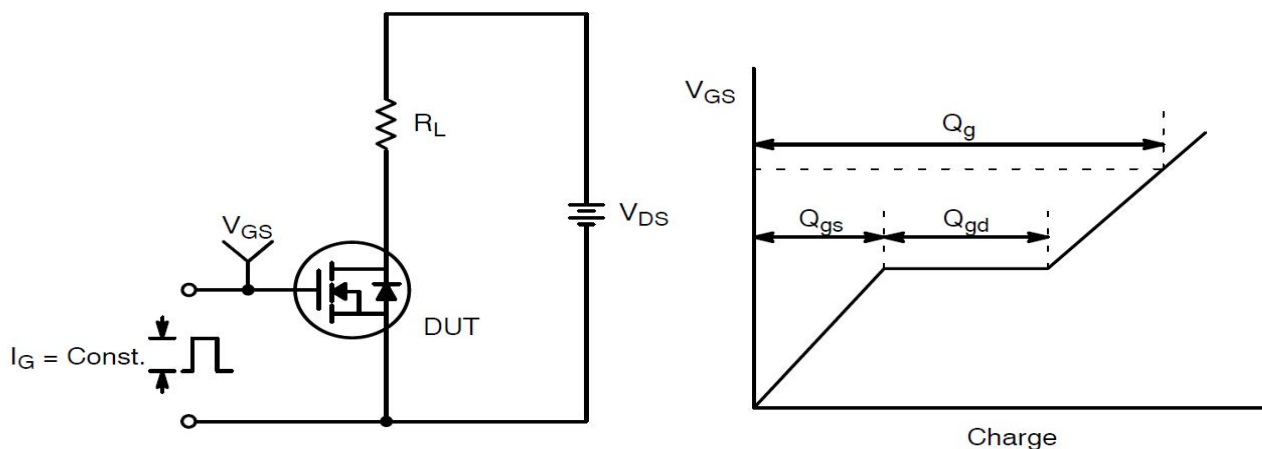


Figure.1: Gate Charge Test Circuit & Waveform

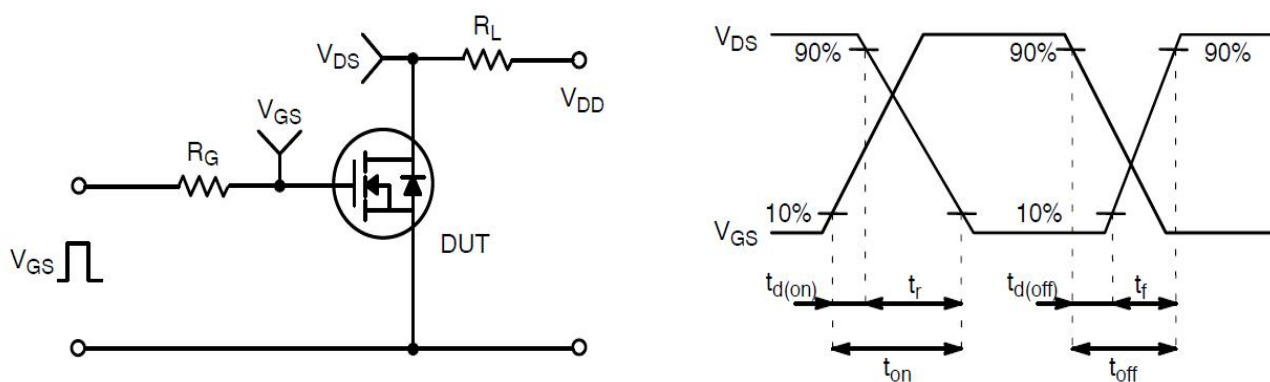


Figure.2: Resistive Switching Test Circuit & Wave forms

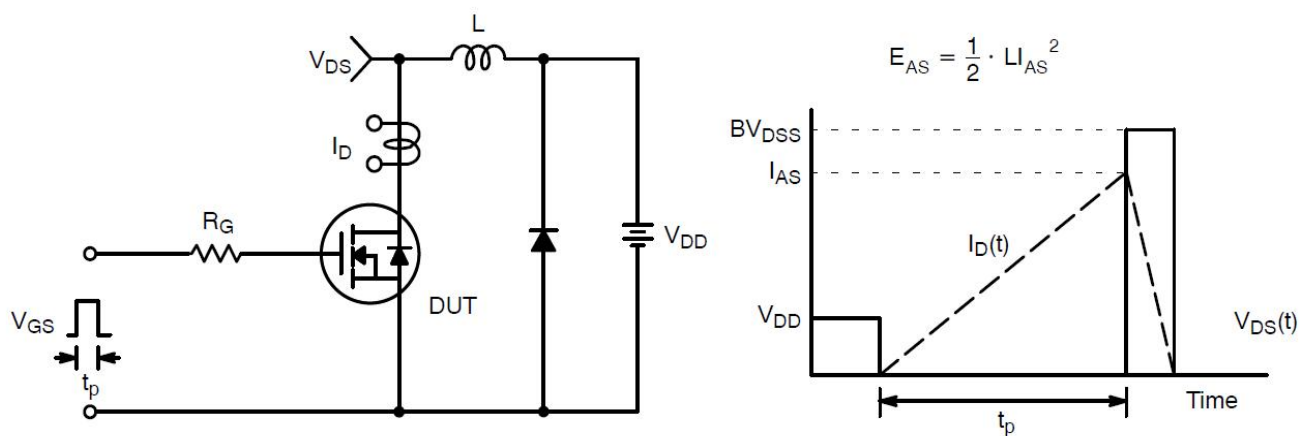
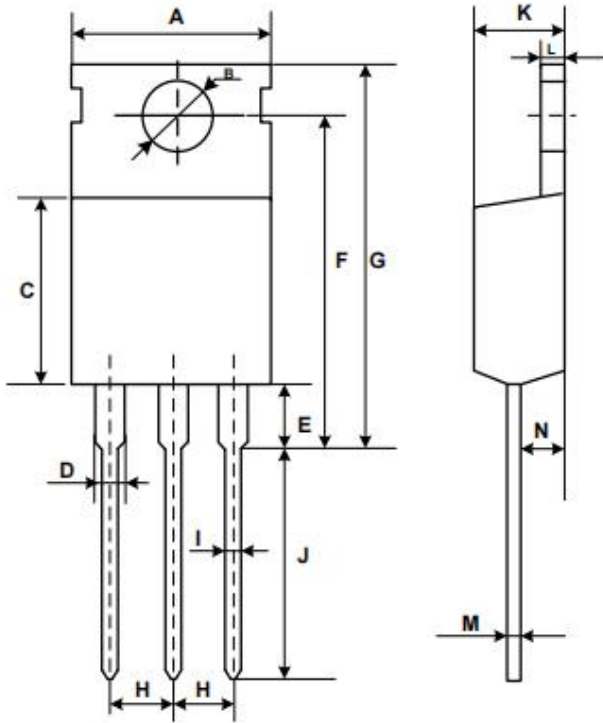


Figure.3: Unclamped inductive Switching Test Circuit & Wave forms



Package Dimensions TO-220

COMMON DIMENSIONS



SYMBOL	MM	
	MIN	MAX
A	9.70	10.30
B	3.40	3.80
C	8.80	9.40
D	1.17	1.47
E	2.60	3.50
F	15.10	16.70
G	19.55MAX	
H	2.54REF	
I	0.70	0.95
J	9.35	11.00
K	4.30	4.77
L	1.20	1.45
M	0.40	0.65
N	2.20	2.60



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